

#### US00D566592S

### (12) United States Design Patent (10) Patent No.:

Nelson et al.

## (45) Patent Pro.: (45) Date of Patent:

US D566,592 S

\*\* Apr. 15, 2008

## (54) FRONT PANEL FOR MEASUREMENT INSTRUMENTS

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#### (\*\*) Term: 14 Years

- (21) Appl. No.: 29/276,744
- (22) Filed: Feb. 2, 2007

(22	) The	u. Feb. 2, 2007	
(51	) <b>LO</b> (	C (8) Cl	10-04
(52	) <b>U.S.</b>	. Cl D1	<b>0/80</b> ; D10/103
(58	) Field	d of Classification Search	324/156,
•	•	324/157, 131, 132, 116, 72.5,	107, 110, 114,
		324/115, 142, 127, 151 A, 15	1 R; 329/110,
		329/155, 156; 337/112, 327,	360; 340/653,
		340/660; 379/21; 439/482;	/
		D24/232–234; D10/80, 102–	
		D14/440, 441; 24/280; 73/	,
		116/DIG. 47; 220/214; 23	, , ,
		292/37 R, 256.67;	301/666, 669

#### See application file for complete search history.

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#### (57) CLAIM

The ornamental design of a front panel for measurement instruments, as shown and described.

#### **DESCRIPTION**

- FIG. 1 is a perspective view of a first embodiment of front panel for measurement instruments;
- FIG. 2 is a front elevation view of the first embodiment of front panel for measurement instruments;
- FIG. 3 is a left side elevation view of the first embodiment of front panel for measurement instruments;
- FIG. 4 is a right side elevation view of the first embodiment of front panel for measurement instruments;
- FIG. 5 is a top plan view of the first embodiment of front panel for measurement instruments;
- FIG. 6 is a bottom plan view of the first embodiment of front panel for measurement instruments;
- FIG. 7 is a perspective view of a second embodiment of front panel for measurement instruments;
- FIG. 8 is a front elevation view of the second embodiment of front panel for measurement instruments;
- FIG. 9 is a left side elevation view of the second embodiment of front panel for measurement instruments;
- FIG. 10 is a right side elevation view of the second embodiment of front panel for measurement instruments;
- FIG. 11 is a top plan view of the second embodiment of front panel for measurement instruments;
- FIG. 12 is a bottom plan view of the second embodiment of front panel for measurement instruments;
- FIG. 13 is a perspective view of a third embodiment of front panel for measurement instruments;
- FIG. 14 is a front elevation view of the third embodiment of front panel for measurement instruments;
- FIG. 15 is a left side elevation view of the third embodiment of front panel for measurement instruments;
- FIG. 16 is a right side elevation view of the third embodiment of front panel for measurement instruments;

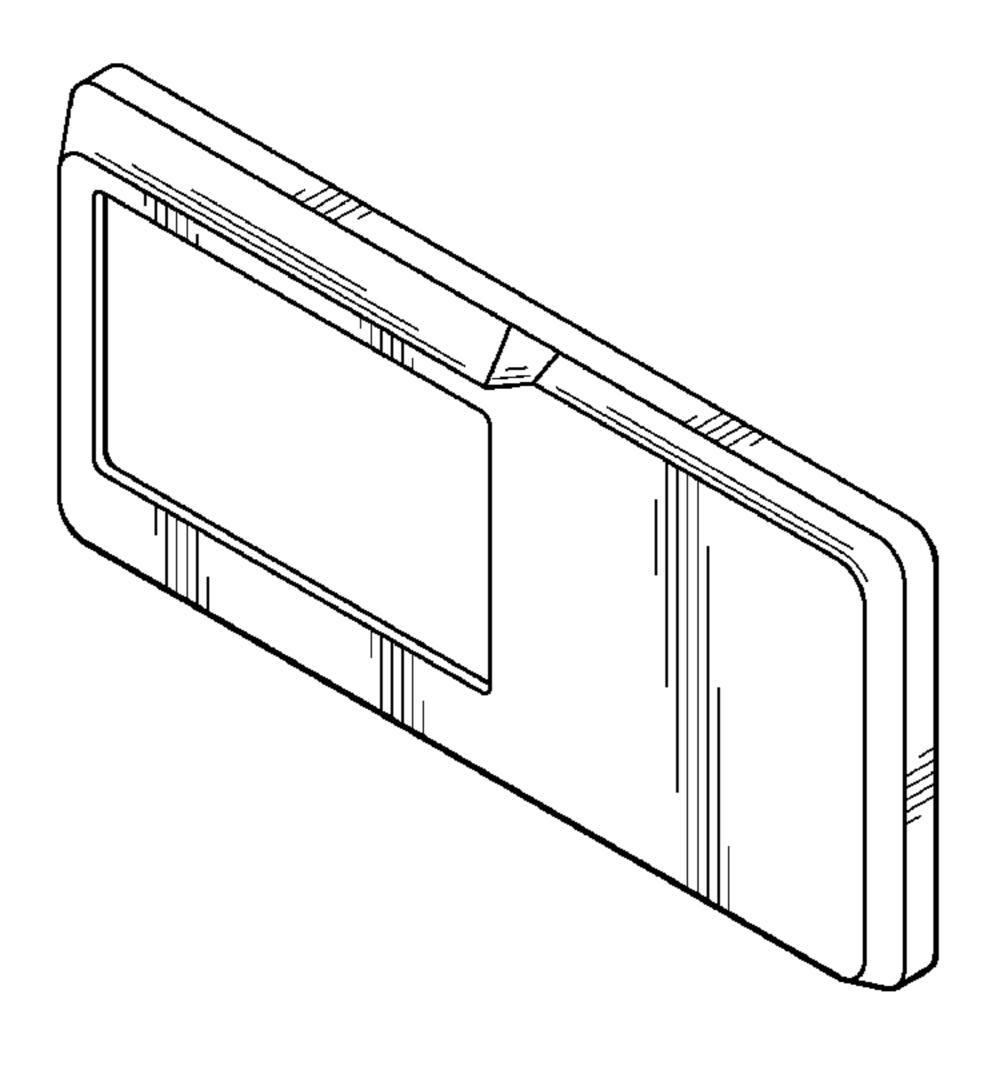


FIG. 17 is a top plan view of the third embodiment of front panel for measurement instruments; and,

FIG. 18 is a bottom plan view of third embodiment of front panel for measurement instruments.

The ornamental design disclosed in this application is for various embodiments of a front panel for measurement instruments, such as oscilloscopes, logic analyzers, waveform generators, and the like. The front panel has a substantially rectangular front face with a substantially rectan-

gular opening disposed in a portion thereof, first beveled surfaces extending from side and bottom surfaces and from a first portion of a top surface to the rectangular front face, and a second beveled surface extending from a second portion of the top surface to the rectangular front face with the second beveled surface laterally transitioning from the first beveled surface.

1 Claim, 6 Drawing Sheets

